



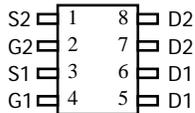
AO4802, AO4802L (Green Product)
Dual N-Channel Enhancement Mode Field Effect Transistor

General Description

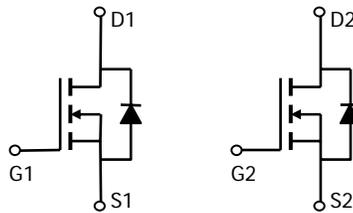
The AO4802 uses advanced trench technology to provide excellent $R_{DS(ON)}$ and low gate charge. They offer operation over a wide gate drive range from 1.8V to 12V. The two devices may be used individually, in parallel or to form a bidirectional blocking switch. AO4802L (Green Product) is offered in a lead-free package.

Features

- V_{DS} (V) = 30V
- I_D = 7A
- $R_{DS(ON)} < 26m\Omega$ ($V_{GS} = 10V$)
- $R_{DS(ON)} < 30m\Omega$ ($V_{GS} = 4.5V$)
- $R_{DS(ON)} < 40m\Omega$ ($V_{GS} = 2.5V$)
- $R_{DS(ON)} < 70m\Omega$ ($V_{GS} = 1.8V$)



SOIC-8



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 12	V
Continuous Drain Current ^A	I_D	$T_A=25^\circ C$	7
		$T_A=70^\circ C$	6
Pulsed Drain Current ^B	I_{DM}	40	A
Power Dissipation	P_D	$T_A=25^\circ C$	2
		$T_A=70^\circ C$	1.44
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	$^\circ C$

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	$t \leq 10s$	48	$^\circ C/W$
Maximum Junction-to-Ambient ^A		Steady-State	74	$^\circ C/W$
Maximum Junction-to-Lead ^C	$R_{\theta JL}$	35	40	$^\circ C/W$

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =250μA, V _{GS} =0V	30			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =24V, V _{GS} =0V T _J =55°C			1 5	μA
I _{GSS}	Gate-Body leakage current	V _{DS} =0V, V _{GS} =±12V			100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} I _D =250μA	0.6	0.8	1	V
I _{D(ON)}	On state drain current	V _{GS} =4.5V, V _{DS} =5V	30			A
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =10V, I _D =7A T _J =125°C		22 28	26 36	mΩ
		V _{GS} =4.5V, I _D =6A		25	30	
		V _{GS} =2.5V, I _D =4A		34	40	mΩ
		V _{GS} =1.8V, I _D =2A		52	70	mΩ
g _{FS}	Forward Transconductance	V _{DS} =5V, I _D =5A	12	17		S
V _{SD}	Diode Forward Voltage	I _S =1A		0.66	1	V
I _S	Maximum Body-Diode Continuous Current				3	A
DYNAMIC PARAMETERS						
C _{ISS}	Input Capacitance	V _{GS} =0V, V _{DS} =15V, f=1MHz		767		pF
C _{OSS}	Output Capacitance			111		pF
C _{RSS}	Reverse Transfer Capacitance			82		pF
R _g	Gate resistance	V _{GS} =0V, V _{DS} =0V, f=1MHz		1.3		Ω
SWITCHING PARAMETERS						
Q _g	Total Gate Charge	V _{GS} =4.5V, V _{DS} =15V, I _D =7A		10		nC
Q _{gs}	Gate Source Charge			1.2		nC
Q _{gd}	Gate Drain Charge			3.1		nC
t _{D(on)}	Turn-On DelayTime	V _{GS} =10V, V _{DS} =15V, R _L =2.2Ω, R _{GEN} =6Ω		5		ns
t _r	Turn-On Rise Time			5.5		ns
t _{D(off)}	Turn-Off DelayTime			39		ns
t _f	Turn-Off Fall Time			4.7		ns
t _{rr}	Body Diode Reverse Recovery time	I _F =5A, dI/dt=100A/μs		15		ns
Q _{rr}	Body Diode Reverse Recovery charge	I _F =5A, dI/dt=100A/μs		7.1		nC

A: The value of R_{θJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The value in any a given application depends on the user's specific board design. The current rating is based on the t_s 10s thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The R_{θJA} is the sum of the thermal impedance from junction to lead R_{θJL} and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using 80μs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

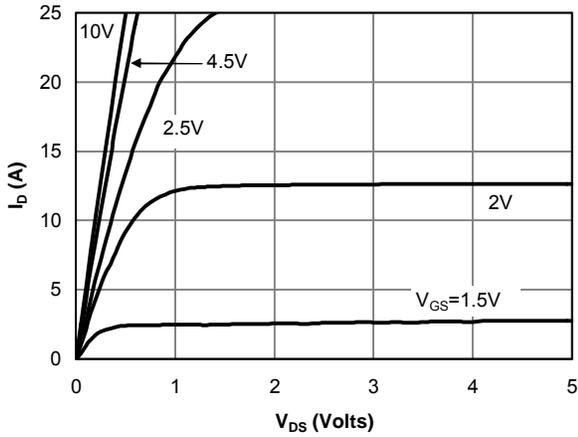


Fig 1: On-Region Characteristics

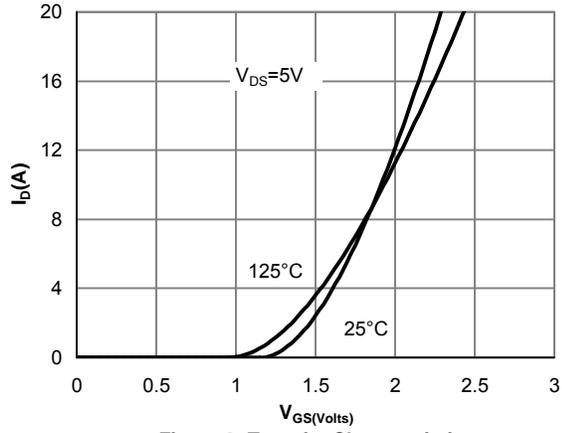


Figure 2: Transfer Characteristics

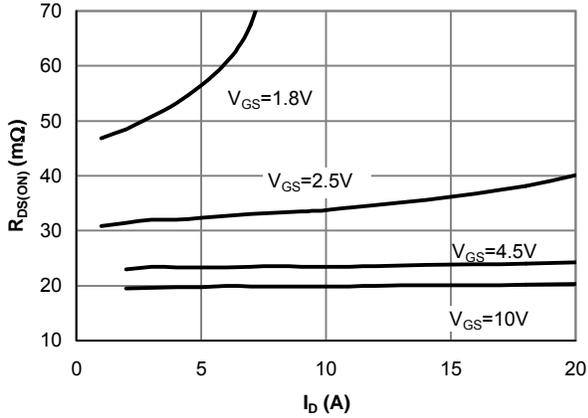


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

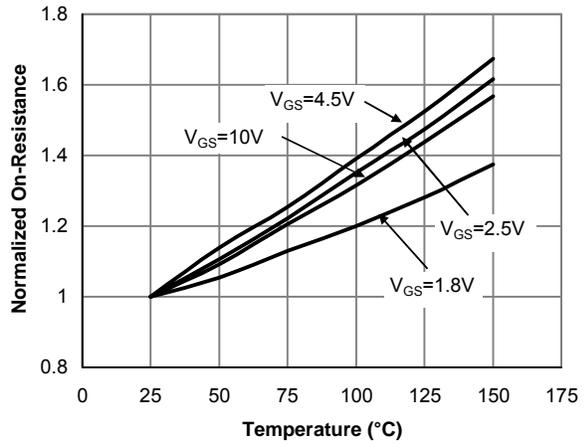


Figure 4: On-Resistance vs. Junction Temperature

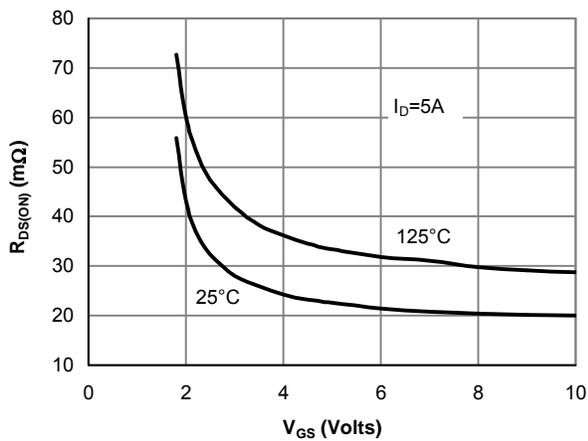


Figure 5: On-Resistance vs. Gate-Source Voltage

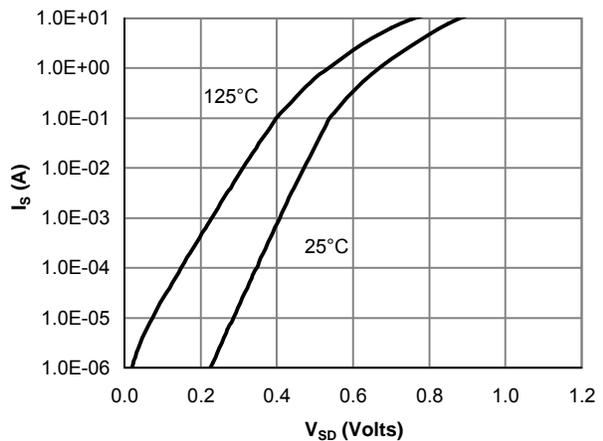


Figure 6: Body-Diode Characteristics

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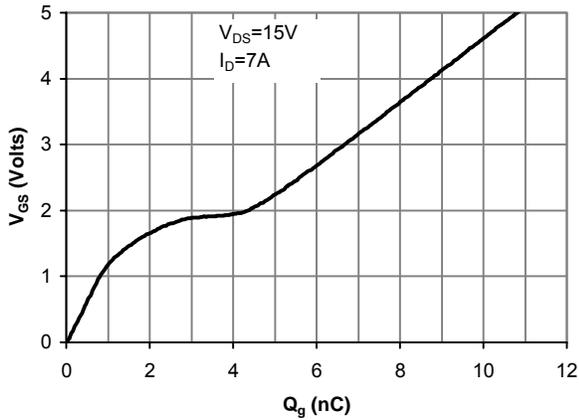


Figure 7: Gate-Charge Characteristics

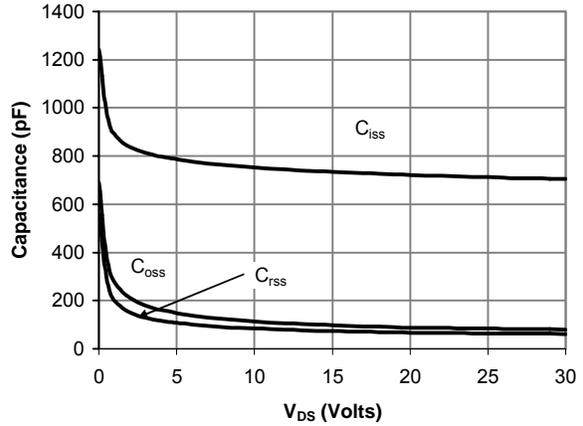


Figure 8: Capacitance Characteristics

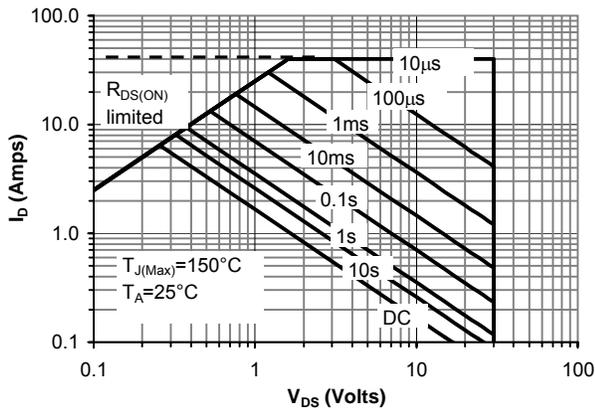


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

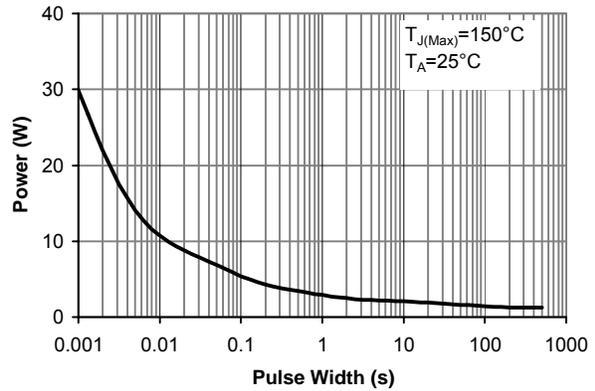


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

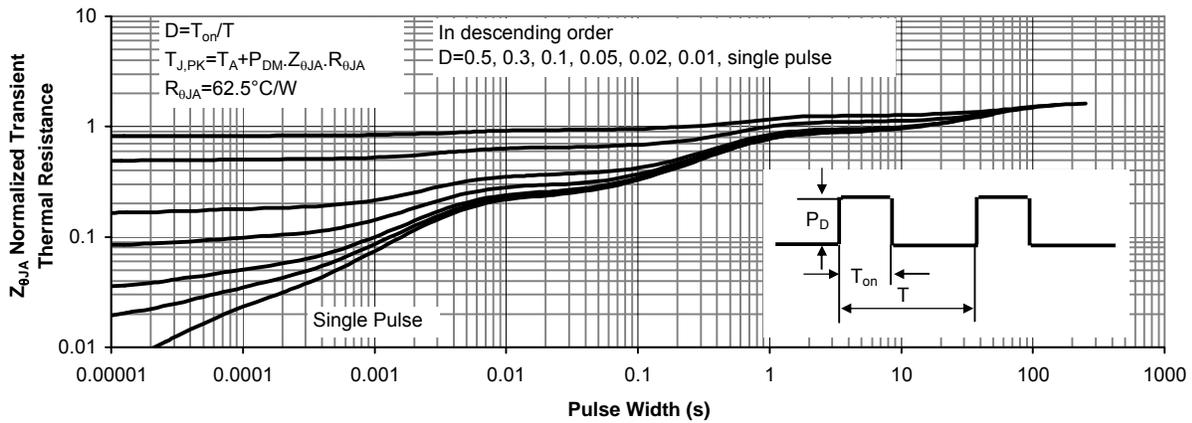


Figure 11: Normalized Maximum Transient Thermal Impedance